

# <complex-block>

Automate your Atom Probe analysis Accelerate your time to knowledge





## Automated Sample Alignment Package

#### Align your microtips at the push of a button.

Included in Package 1:

- Automatic microtip alignment
- Automatic alignment optimization
- Auto local electrode testing

The Automated Sample Alignment Package greatly improves the ease-of-operation of your Atom Probe, reducing the training required for new users and the support needed for infrequent operators.

The data quality benefits from consistent, optimized alignments and frequent local electrode monitoring enabled by the push of a button. The increased frequency of the simple automated test allows local electrode quality to be actively monitored, such that any loss of performance can be preempted, and data quality maintained.





Assessment of the hit pattern on the detector to optimize the alignment.

# Application Expansion Package

## Gain a deeper understanding of your samples.

Includes all Package 1 features:

- Automatic microtip alignment
- Automatic alignment optimization
- Auto local electrode testing

#### Plus:

- Scripted acquisition
- Tool-to-tool matching (TTTM)
- Thirty hours of support
- One box of ten, 25-specimen FT arrays
- One box of ten, 25-specimen PS arrays
- Ten 25-specimen holders

The Application Expansion Package offers all the benefits of the Automated Sample Alignment Package and adds essential automation features to improve measurement consistency and control.

The TTTM feature corrects subtle laser spot size variations to ensure improved long-term instrument stability and enhanced statistical process control, allowing consistent recipes over time and across different tools. The scripted acquisition feature allows optimization of data quality, yield, and throughput by triggering custom acquisition parameter changes in response to the live data stream.



High detection rate for good signal to noise ratio in the implanted region.

Change to low detection rate to minimize risk of fracture at a fragile layer.

Change to high detection rate in the substrate for throughput.

### The Comprehensive LEAP Automation Package

# Run your Atom Probe analysis in continuous unattended mode.

Includes all Package 1 features:

- Automatic microtip alignment
- Automatic alignment optimization
- Auto local electrode testing

As well as all Package 2 features:

- Scripted acquisition
- Tool-to-tool matching (TTTM)

Plus:

- Project plan
- Chain acquisition
- Sixty hours of support
- Ten boxes of ten, 25-specimen FT arrays
- One box of ten, 25-specimen PS arrays
- Twenty 25-specimen holders

To truly unlock the throughput of the LEAP, the Comprehensive Automation Package provides the infrastructure to tie all of the automation features together enabling continuous unattended Atom Probe analysis.

A Project Plan consists of a set of predefined recipes encompassing all steps of the APT project, from data acquisition to reconstruction and analysis, saving tremendous time and effort. All recipes are stored in a library and can be loaded at any time.

Acquisition recipes are fully compatible with the scripted acquisition feature, allowing easy monitoring of the specimen and intelligent variation of all acquisition parameters. The Chain Acquisition feature enables increased levels of LEAP utilization: depending on the time per experiment, chain acquisition on a 25 specimen array can keep a LEAP operating unattended from 12 hours (overnight) to over 48 hours (through a weekend). Acquisition recipes and scripts can be varied across specimens on the array, allowing the unattended operation to be optimally configured for different specimens with different analytical objectives.



## LEAP<sup>®</sup> Automation Packages

Whether in industry or in academic research, Atom Probe users need to acquire data rapidly and efficiently. To address the growing demand for fast and unattended analysis of large numbers of samples, CAMECA introduces a set of automation packages for the LEAP 5000 Atom Probe.

From sample alignment to scripted and chain acquisition or tool-to-tool matching, our three packages address several levels of automation requirements. They significantly increase the instrument's ease-of-use, improve measurement stability, provide tools to optimize data quality and yield, and greatly improve productivity.

All three packages are available as options to the AP Suite 6.1 software platform.



and the second s		
come y competence a co		
teres teres ter	and the general the second state of the second	
terms had	Suttaneed Steals	
City Provent	Landrama	in the second
and the second se	Marrisg Rever Diseased (10 has doe with 10 has been	
and some income the spinor and they	The superior of second discountered and of the	
Including Cold Cold Cold Cold Cold Cold Cold Cold	NUMBER OF A DESCRIPTION	
AAPU DA	Constrained Within 1980	
	of second later 1988	
	Annual of the Annual of Context of	
APRIL A	the property in the party of the second second second	
aver	Characteristic UPI Scale History Plot	
	i land a second and	a de
Careful a		
ANDINE		
	1	
	C. C. Martine and C.	
	conversion insurant responses and a	0.00.00
	Tono and Your of the logarithmet	

The new tool-to-tool matching feature enables easy and efficient monitoring of multiple tools, high productivity and data consistency.

**CAMECA (Corporate Headquarters)** 29 Quai des Grésillons 92622 Gennevilliers Cedex - France Tel: +33 1 43 34 62 00

cameca.info@ametek.com

**CAMECA Atom Probe Technology Center** 5470 Nobel Drive Madison, WI 53711 - USA Tel: +1 608 274 6880

#### www.cameca.com

B-APT-AUTO March 2021. Non-contractual document, CAMECA reserves the right to alter the specifications of its products without notice. All mentioned trademarks are reigsterered by their respective owners.





